

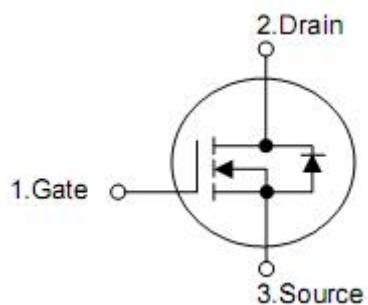
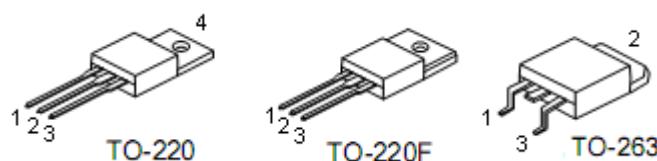
1. Description

The KIA13N50H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology

2. Features

- $R_{DS(on)}=0.4\Omega$ @ $V_{GS}=10V$
- Low gate charge (typical 45nC)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

3. Pin configuration



| Pin | Function |
|-----|----------|
| 1 | Gate |
| 2 | Drain |
| 3 | Source |
| 4 | Drain |

4. Absolute maximum ratings

| Parameter | | Symbol | Ratings | | | Units |
|------------------------------------|---------------------------------|-----------|--------------------|--------|-------|---------------------|
| | | | TO220 | TO220F | TO263 | |
| Drain-source voltage | | V_{DSS} | 500 | | | V |
| Gate-source voltage | | V_{GSS} | ± 30 | | | V |
| Drain current continuous | $T_c=25^\circ\text{C}$ | I_D | 13.0 | 13.0* | 13.0 | A |
| | $T_c=100^\circ\text{C}$ | | 8.0 | 8.0* | 8.0 | A |
| Drain current pulsed (note1) | | I_{DP} | 52.0 | 52.0* | 52.0 | A |
| Avalanche energy | Repetitive (note1) | E_{AR} | 19.5 | | | mJ |
| | Single pulse (note2) | E_{AS} | 860 | | | mJ |
| Peak diode recovery dv/dt (note 3) | | dv/dt | 4.5 | | | V/ns |
| Total power dissipation | $T_c=25^\circ\text{C}$ | P_D | 195 | 48 | 195 | W |
| | derate above 25°C | | 1.56 | 0.39 | 1.56 | W/ $^\circ\text{C}$ |
| Junction temperature | | T_J | $+150$ | | | $^\circ\text{C}$ |
| Storage temperature | | T_{STG} | $-55\text{--}+150$ | | | $^\circ\text{C}$ |

*Drain current limited by maximum junction temperature.

5. Thermal characteristics

| Parameter | | Symbol | Ratings | | | Units |
|---------------------------------------|--|------------|---------|--------|-------|---------------------------|
| | | | TO220 | TO220F | TO263 | |
| Thermal resistance, junction-ambient | | R_{thJA} | 62.5 | | | $^\circ\text{C}/\text{W}$ |
| Thermal resistance, case-to-sink typ. | | R_{thJS} | 0.5 | - | 0.5 | |
| Thermal resistance, Junction-case | | R_{thJC} | 0.64 | 2.58 | 0.64 | |

6. Electrical characteristics

($T_J=25^\circ\text{C}$, unless otherwise notes)

| Parameter | Symbol | Conditions | Min | Typ | Max | Units |
|---|--|--|-----|------|------|---------------------------|
| Off characteristics | | | | | | |
| Drain-source breakdown voltage | BV_{DSS} | $V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$ | 500 | - | - | V |
| Zero gate voltage drain current | $I_{\text{DS}}^{\text{SS}}$ | $V_{\text{DS}}=500\text{V}, V_{\text{GS}}=0\text{V}$ | - | - | 1 | μA |
| | | $V_{\text{DS}}=400\text{V}, T_c=125^\circ\text{C}$ | - | - | 10 | μA |
| Gate-body leakage current | I_{GSS} | $V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$ | - | - | 100 | nA |
| | | $V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$ | - | - | -100 | nA |
| Breakdown voltage temperature coefficient | $\Delta \text{BV}_{\text{DSS}}/\Delta T_J$ | $I_{\text{D}}=250\mu\text{A}$ | - | 0.5 | - | $\text{V}/^\circ\text{C}$ |
| On characteristics | | | | | | |
| Gate threshold voltage | $V_{\text{GS}(\text{th})}$ | $V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$ | 2.0 | - | 4.0 | V |
| Static drain-source on-resistance | $R_{\text{DS}(\text{on})}$ | $V_{\text{GS}}=10\text{V}, I_{\text{D}}=6.5\text{A}$ | - | 0.4 | 0.48 | Ω |
| Dynamic characteristics | | | | | | |
| Input capacitance | C_{iss} | $V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$ | - | 1600 | - | pF |
| Output capacitance | C_{oss} | | - | 200 | - | pF |
| Reverse transfer capacitance | C_{rss} | | - | 20 | - | pF |
| Switching characteristics | | | | | | |
| Turn-on delay time | $t_{\text{d}(\text{on})}$ | $V_{\text{DD}}=250\text{V}, I_{\text{D}}=13.0\text{A}, R_G=25\Omega$ (note4,5) | - | 25 | - | ns |
| Rise time | t_r | | - | 100 | - | ns |
| Turn-off delay time | $t_{\text{d}(\text{off})}$ | | - | 130 | - | ns |
| Fall time | t_f | | - | 100 | - | ns |
| Total gate charge | Q_g | $V_{\text{DS}}=400\text{V}, I_{\text{D}}=13.0\text{A}, V_{\text{GS}}=10\text{V}$ (note4,5) | - | 45 | - | nC |
| Gate-source charge | Q_{gs} | | - | 8 | - | nC |
| Gate-drain charge | Q_{gd} | | - | 19 | - | nC |
| Drain-source diode characteristics | | | | | | |
| Drain-source diode forward voltage | V_{SD} | $V_{\text{GS}}=0\text{V}, I_{\text{D}}=13.0\text{A}$ | - | - | 1.4 | V |
| Continuous drain-source current | I_{SD} | | - | - | 13.0 | A |
| Pulsed drain-source current | I_{SM} | | - | - | 52.0 | A |
| Reverse recovery time | t_{rr} | $I_{\text{SD}}=13.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note4) | - | 410 | - | ns |
| Reverse recovery charge | Q_{rr} | | - | 4.5 | - | μC |

Note:1 Repetitive rating: pulse width limited by maximum junction temperature

2. $L=6\text{mH}, I_{\text{AS}}=13.0\text{A}, V_{\text{DD}}=50\text{V}, R_G=25\Omega$, starting $T_J=25^\circ\text{C}$

3. $I_{\text{SD}} \leq 13.0\text{A}, dI/dt \leq 200\text{A}/\mu\text{s}, V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$, starting $T_J=25^\circ\text{C}$

4. Pulse test: pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$

5. Essentially independent of operating temperature

7. Typical Characteristics

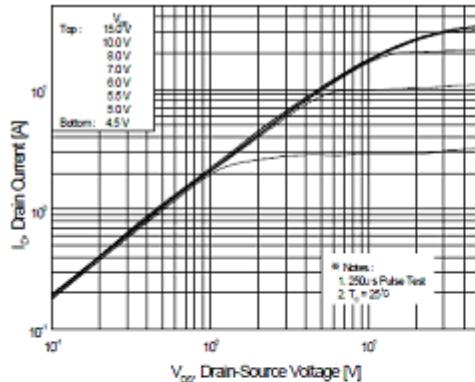


Figure 1. On-Region Characteristics

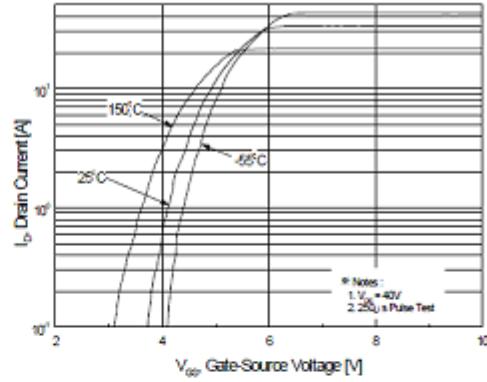


Figure 2. Transfer Characteristics

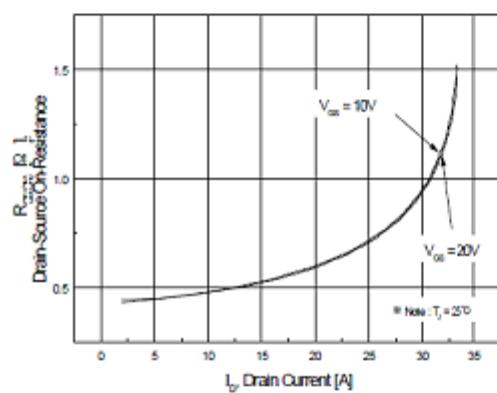


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

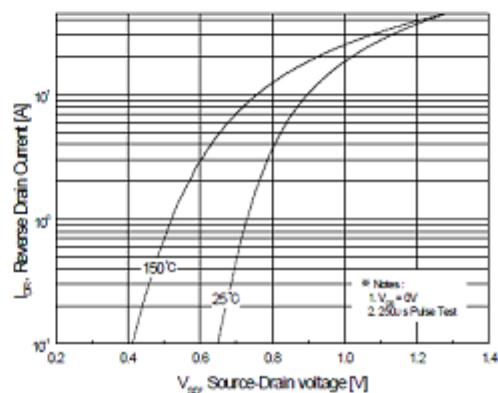


Figure 4. Body Diode Forward Voltage Variation with Source Current

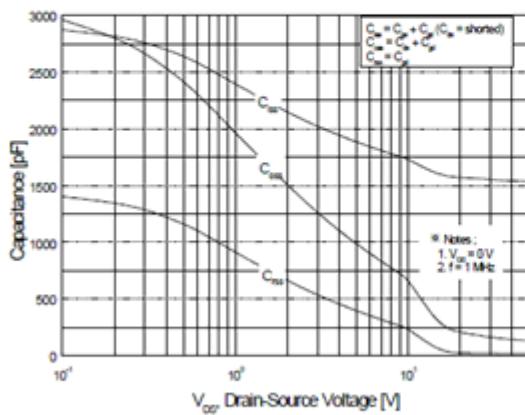


Figure 5. Capacitance Characteristics

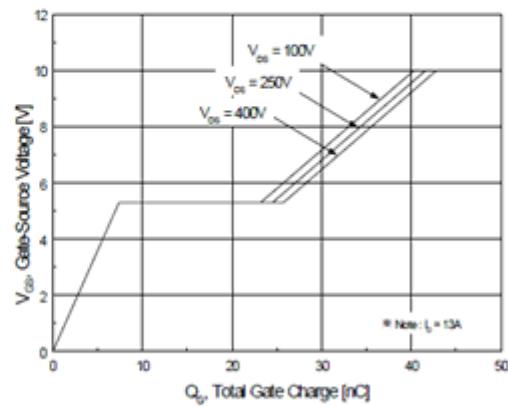


Figure 6. Gate Charge Characteristics

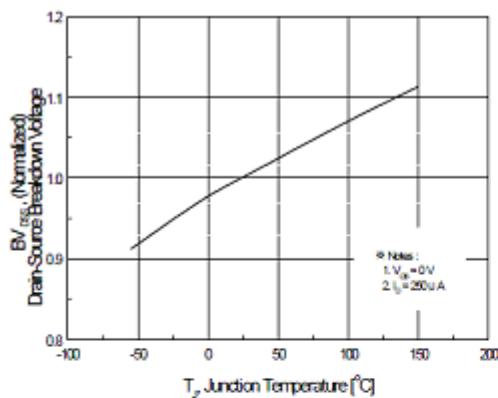


Figure 7. Breakdown Voltage Variation vs Temperature

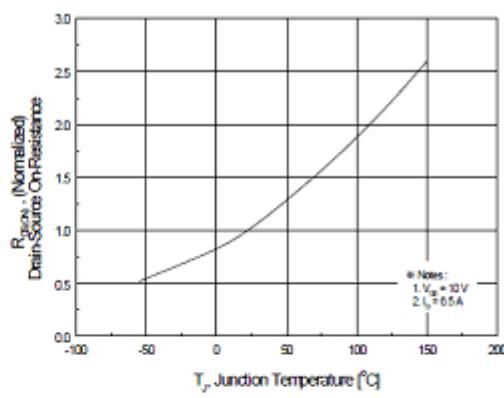


Figure 8. On-Resistance Variation vs Temperature

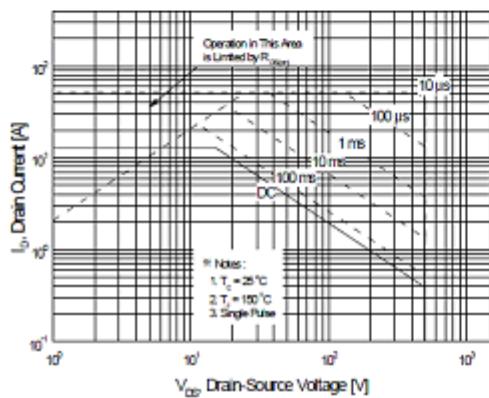


Figure 9. Maximum Safe Operating Area

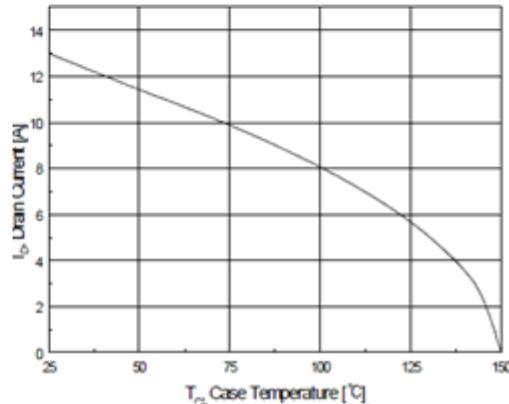


Figure 10. Maximum Drain Current vs Case Temperature

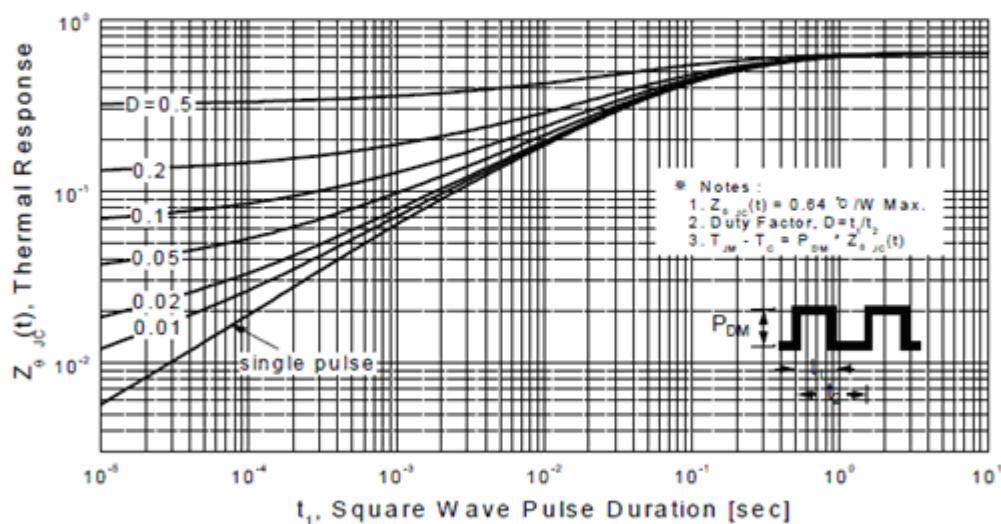


Figure 11. Transient Thermal Response Curve